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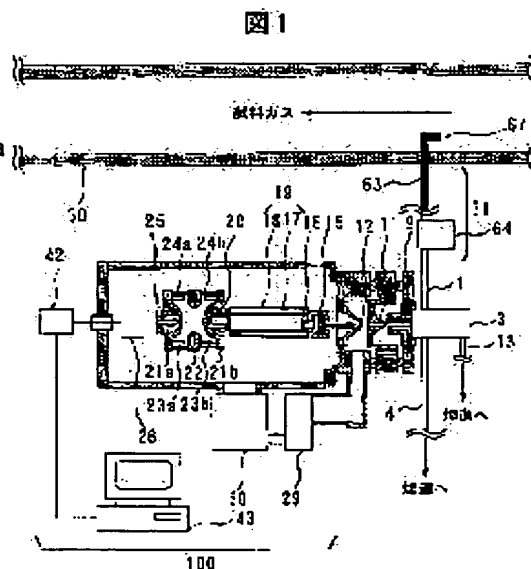
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## (54) IONIZED MASS SPECTROMETER, ANALYSIS METHOD, AND MEASURING SYSTEM USING IONIZED MASS SPECTROMETER

### (57)Abstract:

PROBLEM TO BE SOLVED: To provide an ion source which uses a corona discharge for highly effectively ionizing a sample.

SOLUTION: In a corona discharge for generating ions at the tip of a needle electrode by applying a high voltage, a direction for a sample to be introduced into a range of the corona discharge is almost opposed to the direction for ions to be pulled out, therefore, ion generation efficiency can be improved.



### LEGAL STATUS

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